

Search Notes

Application/Control No.

10/623,912

Examiner

Edward Wojciechowicz

Applicant(s)/Patent under
Reexamination

CHIH ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	314	3-5-05	EF

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR